

**Search Notes****Application/Control No.**

10/517,318

**Examiner**

Emmanuel S. Luk

**Applicant(s)/Patent under Reexamination**

NAITO ET AL.

**Art Unit**

1722

**SEARCHED**

Class	Subclass	Date	Examiner
425	542	3/18/2007	EL
425	416	3/18/2007	EL
83	22	3/18/2007	EL
83	24	3/18/2007	EL
83	99	3/18/2007	EL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search	3/18/2007	EL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner